PCN Num	<b>ber:</b> 201	50224000		<b>PCN Date:</b> 2/25/2015		
Title: Qualification of Aizu as an additional Fab site for select devices in the CMOS9T 5V Fab process.						
Customer	Contact:	PCN Manage	r Dept:	Quality Services		
*Proposed 1 <sup>st</sup> Ship Date:		5/25/2015	Estimated Sam Availability:			
Change Type:			·	<u> </u>		
	mbly Site	Assemt	oly Process	Assembly Materials		
Desig	jn	Electric	al Specification	Mechanical Specification		
Test	Site	Packing	J/Shipping/Labeling	Test Process		
Wafe	r Bump Site	Wafer B	Bump Material	Wafer Bump Process		
🛛 Wafe	r Fab Site	Wafer F	ab Materials	Wafer Fab Process		
		Part nu	mber change			
		Р	CN Details			
Descriptio	on of Change:					
This change notification is to announce the addition of Aizu as an additional Fab site for select devices in the CMOS9T 5V Fab Process in Maine Fab. The affected devices are listed in the "Product Affected" section of this document. <b>Fab Site</b>						
Current	: Site/Process/Wafe	er Diameter	Additional Site/Pro	cess/Wafer Diameter		
MAINEFAB/CMOS9T/200mm AIZU/CMOS9T/200mm						
Reason fo	or Change:					
Continuity of supply.						
Anticipate	ed impact on Fori	m, Fit, Functi	on, Quality or Reliabil	ity (positive / negative):		
None						
	to product identif	fication resul	ting from this PCN:			
Current						
Chip Site		ite Code (20L)		y Code (21 L)		
MAINEFA	В	CUA	(	JSA		
New						
Chip Site	Chip S	ite Code (20L)	Chip Country	y Code (21 L)		
AIZU		CU2	J	IPN		
Sample Product Shipping Label (not actual product label) TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q: MSL 2 /260C/1 YEAR SEAL DT 03/29/04 OPT: ITEM: 39 LBL: 5A (L)T0:1750 (not actual product label) (1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2D) CS0: SHE (21L) CC0:USA (23L) ACO: MYS						
Product A						
LP875484	FQR LP87	5494YFQR				

## **Qualification Report** CMOS9T DGO Process at Aizu Approved 01/11/2015

## Product Attributes

	Qual Device: LP8754YFQ	QBS Process: LM3533TMX-40/NOPB	QBS Process: LP8556TMX-E09/S1	QBS Process: LP5907UVX-3.3
Attributes				
Wafer Fab Site	AIZU	AIZU	AIZU	AIZU
Wafer Fab Process	CMOS9T DGO	CMOS9T	CMOS9T-5V	CMOS9T
Wafer Diameter	200mm	200mm	200mm	200mm

- QBS: Qual By Similarity - Qual Device LP8754YFQ is qualified at LEVEL1-260C

## **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: LP8754YFQ	QBS Process: LM3533TMX-40/NOPB	QBS Process: LP8556TMX-E09/S1	QBS Process: LP5907UVX-3.3
PC	PreCon Level 1	260C	-	3/462/0	3/693/0	3/693/0
HAST	Biased HAST, 110C/85%RH	264 Hours	-	-	2/154/0	-
AC	Autoclave 121C	96 hours	-	3/231/0	-	-
THB	Biased Temperature and Humidity, 85C/85%RH	1000 Hours	-	-	-	3/231/0
UHAST	Unbiased HAST 130C/85%RH	96 Hours	-	-	3/231/0	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	500 Hours	-	-	1/77/0	-
HTOL	Life Test, 125C	1000 Hours	3/231/0	-	-	-
ELFR	Early Life Failure Rate, 125C	48 Hours	3/2449/0	-	-	-
HBM	ESD - HBM	1000 V	3/9/0	-	-	-
CDM	ESD - CDM	750 V	3/9/0	-	-	-
LU	Latch-up	25 C	3/18/0	-	-	-
LU	Latch-up	125 C	3/18/0	-	-	-
ED	Electrical Characterization	-	3/90/0	-		-
DR	Data Retention, 215C	300 Hours	3/231/0	-	-	-
PC	EPROM Power Cycles (on/off)	10,000 Cycles	3/231/0	-	-	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours - The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours - The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
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